

Notice of References Cited		Application/Control No. 09/708,722	Applicant(s)/Patent Under Reexamination JOURDAN ET AL.	
		Examiner Aimee J. Li	Art Unit 2183	Page 1 of 1

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	U	Rotenberg, Eric; Bennet, Steve; Smith, James E. "A Trace Cache Microarchitecture and Evaluation". IEEE ©1999. Pages 111-120.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.